ROCHESTER INSTITUTE OF TECHNOLOGY MICROELECTRONIC ENGINEERING

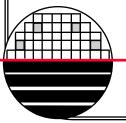
Surface MEMS Design Examples

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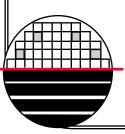
Department webpage: http://www.microe.rit.edu



Rochester Institute of Technology Microelectronic Engineering 10-2-2014 SurfaceMEMsDesignExamples.ppt

OUTLINE

Introduction **Cross Section Test Structures** Cantilever Thermally Actuated Speaker Microphone Chemical/Humidity Sensor Mirror – Electrostatic – Torsional Heater and Sensors AC/DC Switch Thermal Actuators - Microgripper Comb Drive Actuators Probe Resistor-Bolometer Gas Flow Sensor **Peltier Cooling** Magnetic Field Sensor

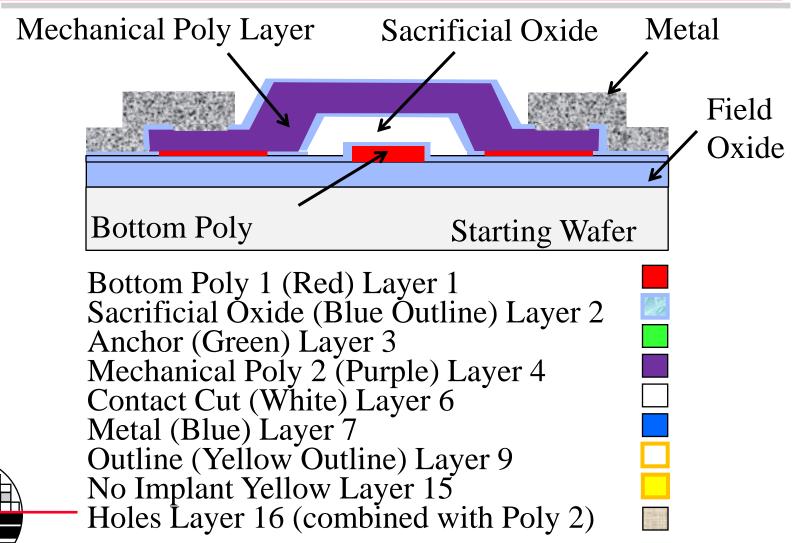


INTRODUCTION

This document provides example layouts for devices made with RIT's surface micromachine process. This process is capable of making many different types of MEMS devices. This MEMS fabrication process is CMOS compatible (with some modifications) back end module that can be added to realize compact microsystems (CMOS plus MEMS).



DEVICE CROSS SECTION



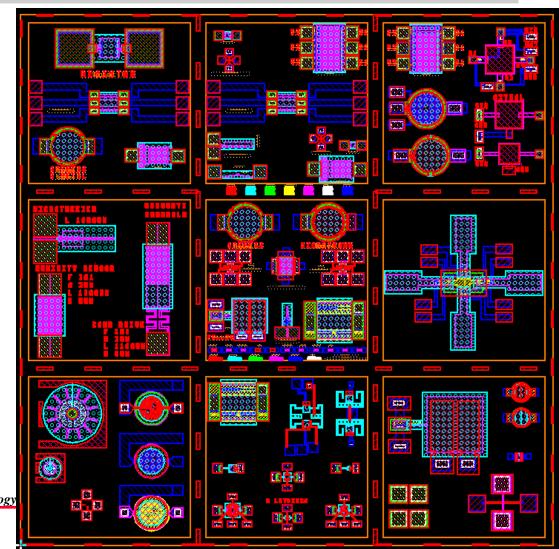


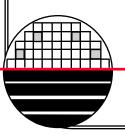
2014 MEMS MULTICHIP PROJECT DESIGN

Total 15 mm by 15 mm plus 500 um for sawing into 9 chips for overall 16.5mm by 16.5mm size.

Wafer sawing is easier if all chips are the same size

5mm by 5mm design space for each project

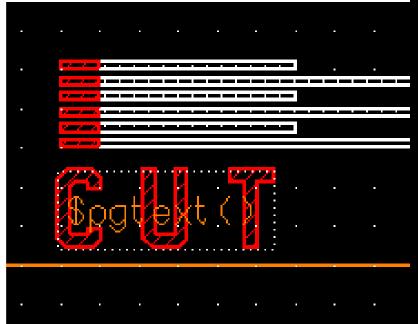




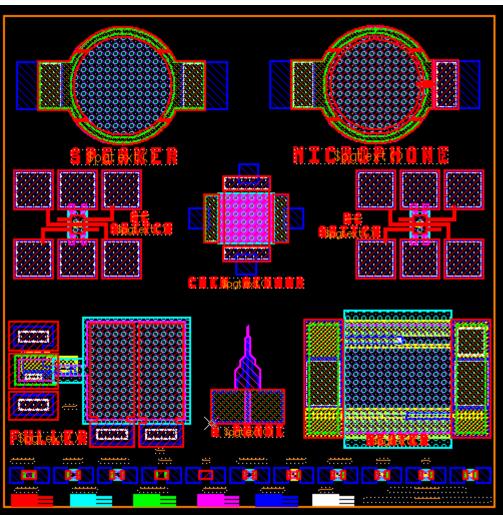
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TEST STRUCTURES

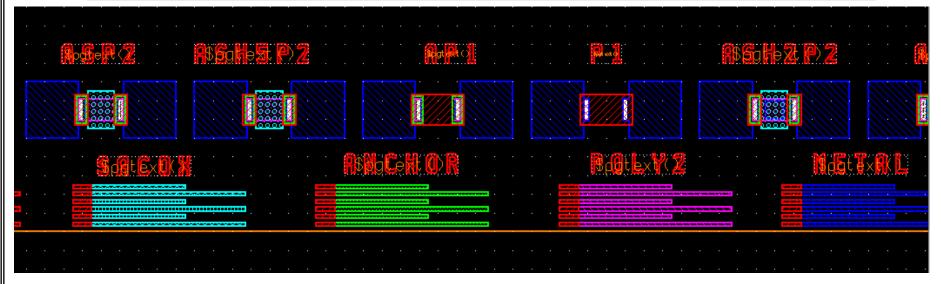
One of the cells will have test structures along the bottom edge for resolution/overlay,etc.



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TEST STRUCTURES



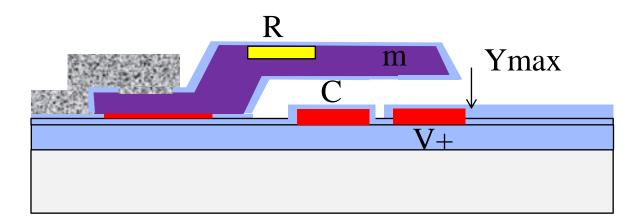
- 1. Poly1 in Parallel with Poly2
- 2. No Etch Holes Poly 2
- 3. 5um Etch Holes Poly2
- 4. Metal contact to Poly2 to Poly1
- 5. Metal contact to Poly1
- 6. 2um Etch Holes Poly2

7. Poly2 No Implant, No SacOx

- 8. Poly2 No Implant
- 9. Poly2 No Implant 5um Gap
- 10. Poly2 No Implant 5um Resistor
- 11. Poly 2 No Implant 10um Resistor

Rochester Institute of Technology Microelectronic Engineering Starting from Left Resistors $L = \sim 100 \mu m$ W = $\sim 50 \mu m$

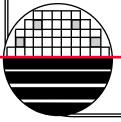
CANTILEVER, MIRROR OR ACCELEROMETER



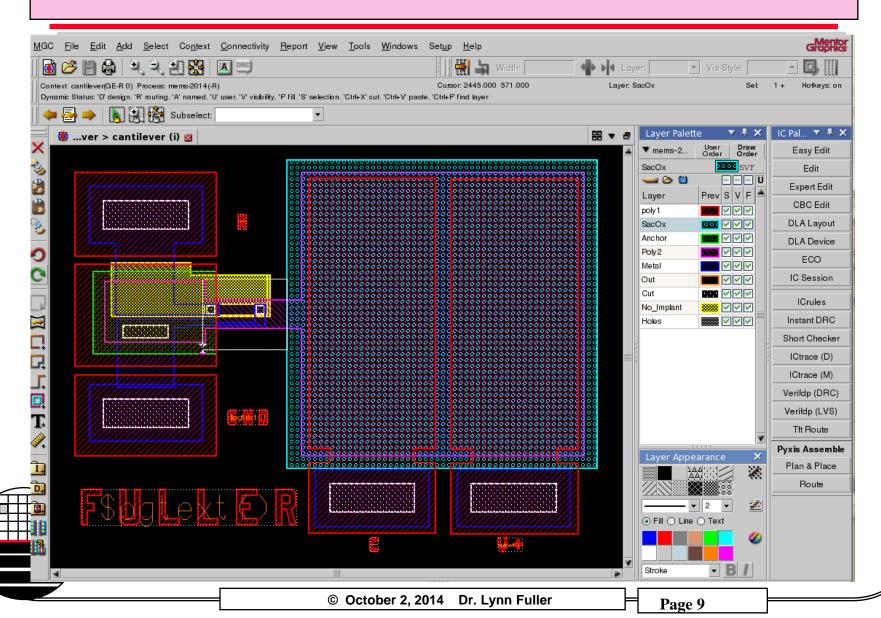
Electrostatic Actuation Capacitor Sensor Resistor Sensor Accelerometer or Mirror



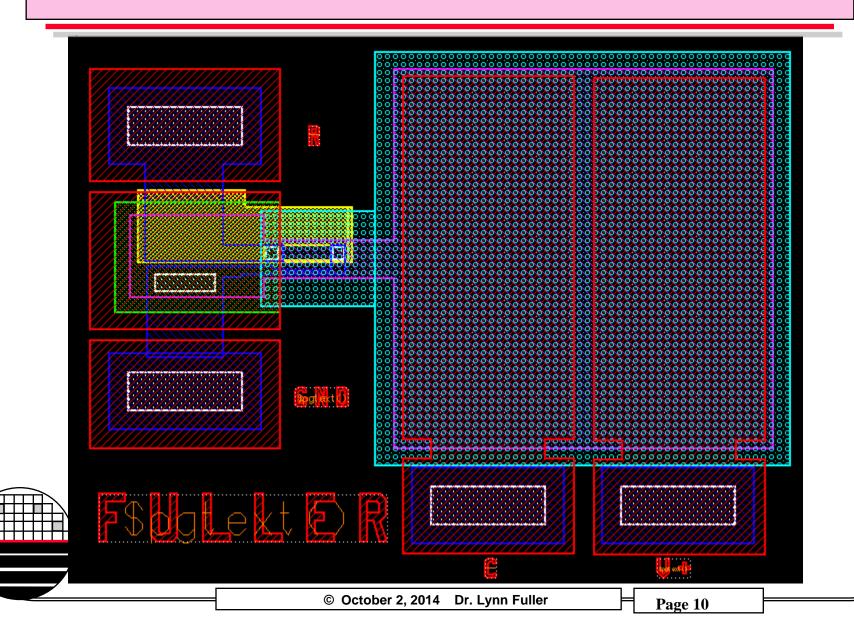
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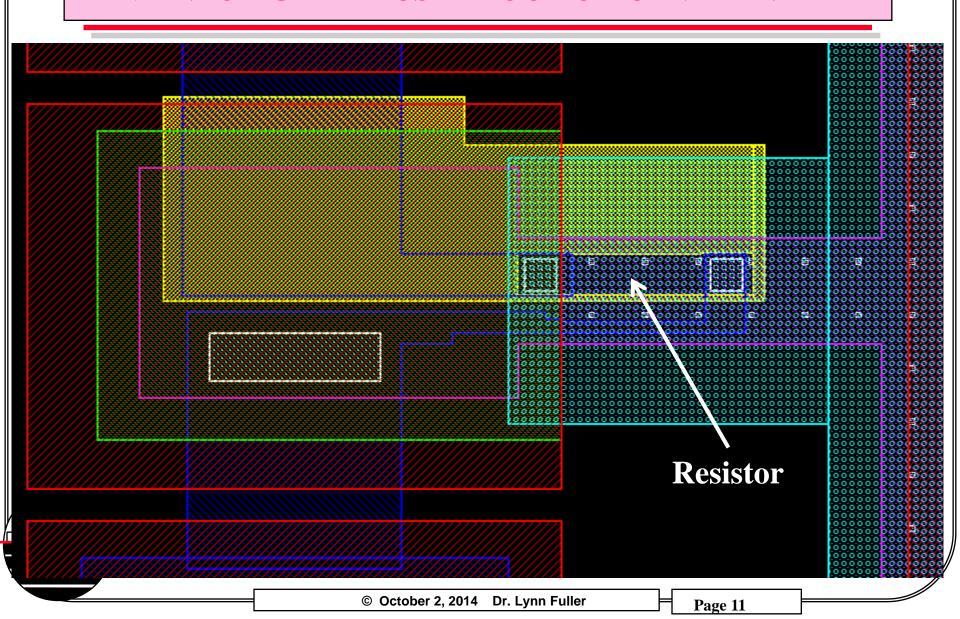
MENTOR GRAPHICS LAYOUT OF CANTILEVER



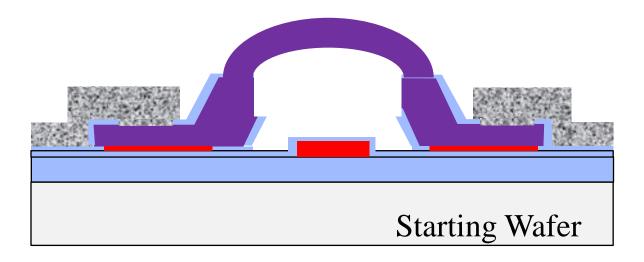
MENTOR GRAPHICS LAYOUT OF CANTILEVER

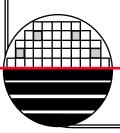


MENTOR GRAPHICS LAYOUT OF CANTILEVER



THERMALLY ACTUATED SPEAKER

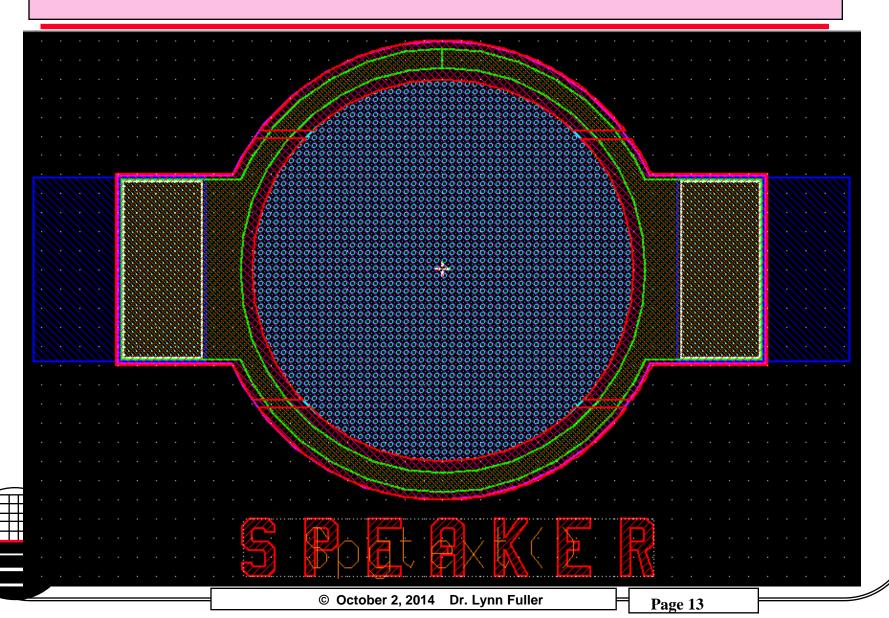




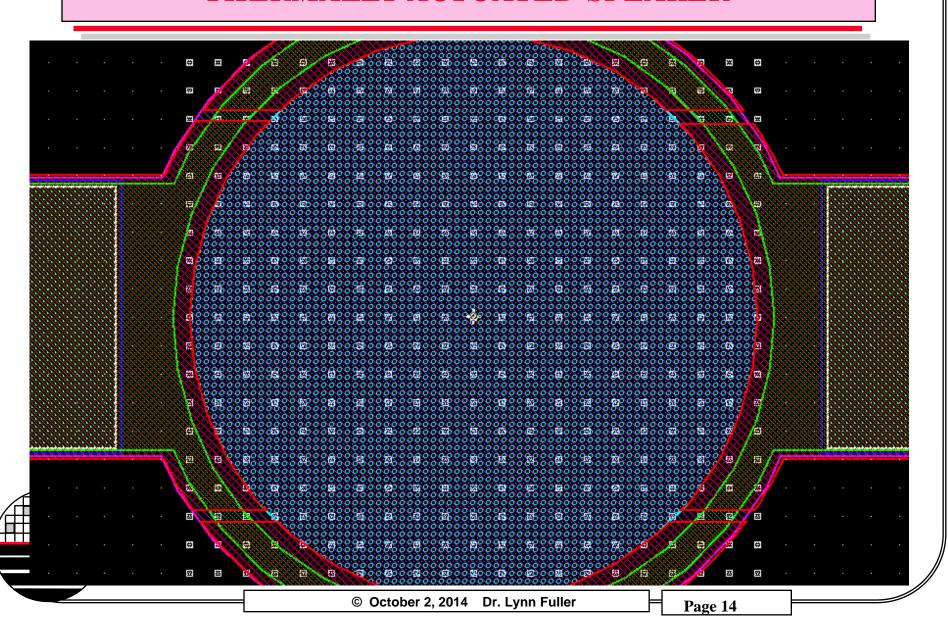
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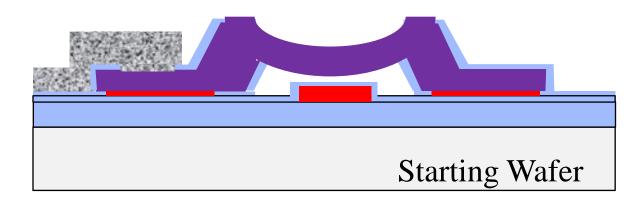
THERMALLY ACTUATED SPEAKER



THERMALLY ACTUATED SPEAKER

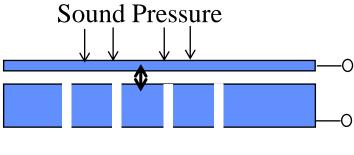


MICROPHONE



Top plate diaphragm

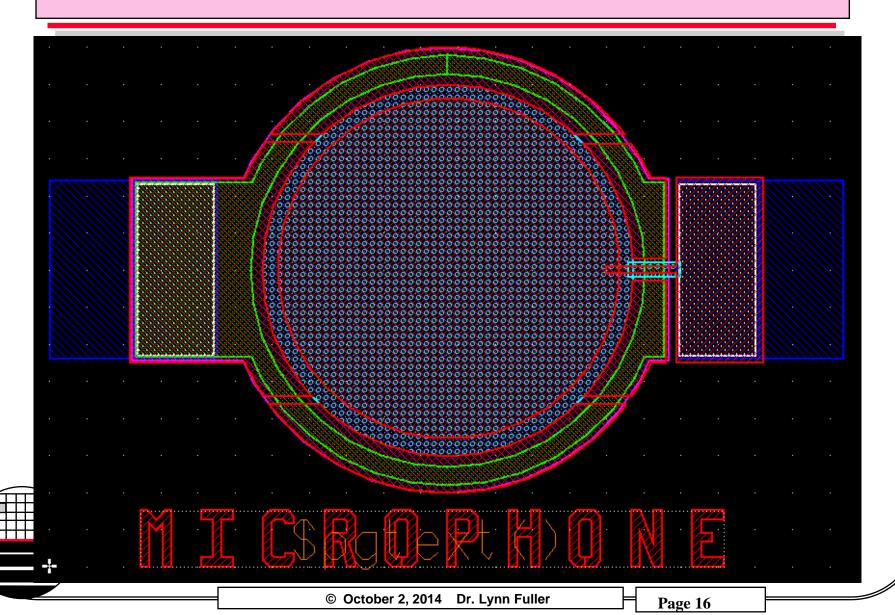
Fixed bottom plate with holes



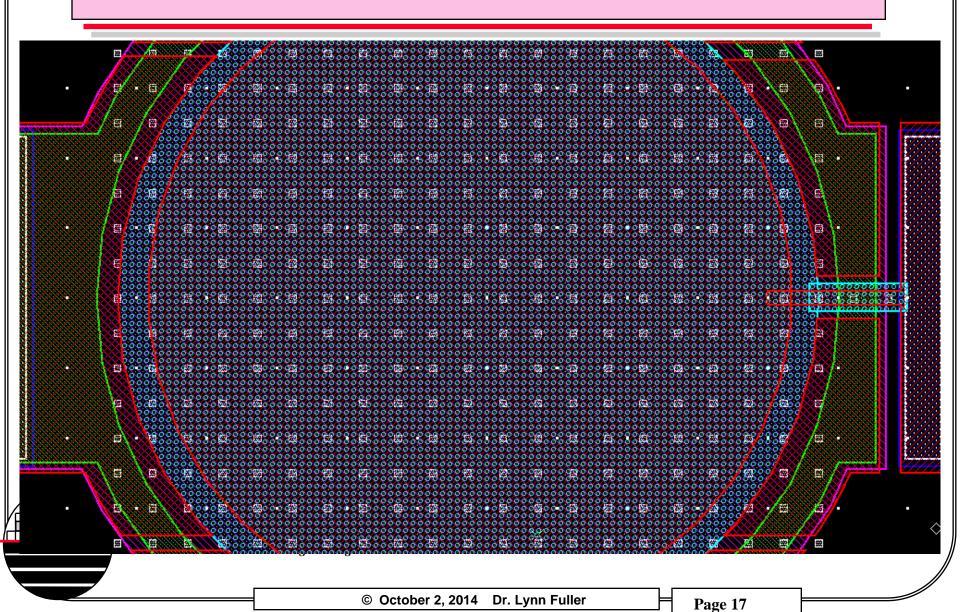
Output
Capacitance



MICROPHONE

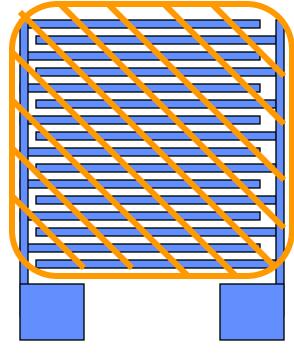


MICROPHONE

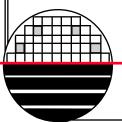


CHEMICAL SENSOR OR HUMIDITY SENSOR

Interdigitated fingers form electrodes for either resistive or capacitive sensors. For capacitive sensors the fingers are closely spaced. The chemically sensitive coating is resistive and the resistance changes in the presence of some chemical to be sensed or the coating is not conductive but the dielectric constant changes in the presence of some chemical to be sensed.



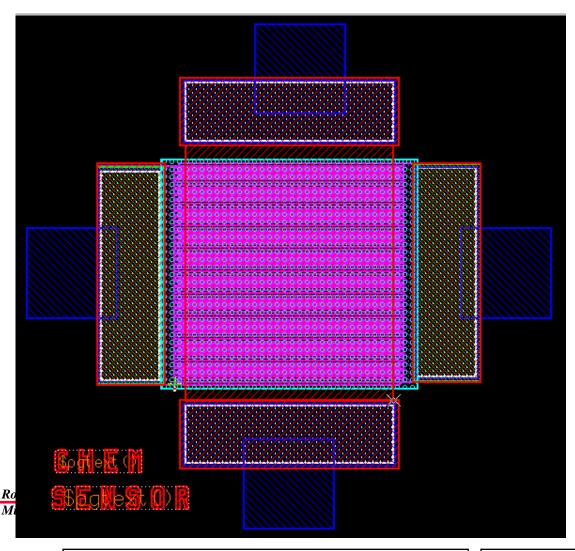
 ΔC or ΔR



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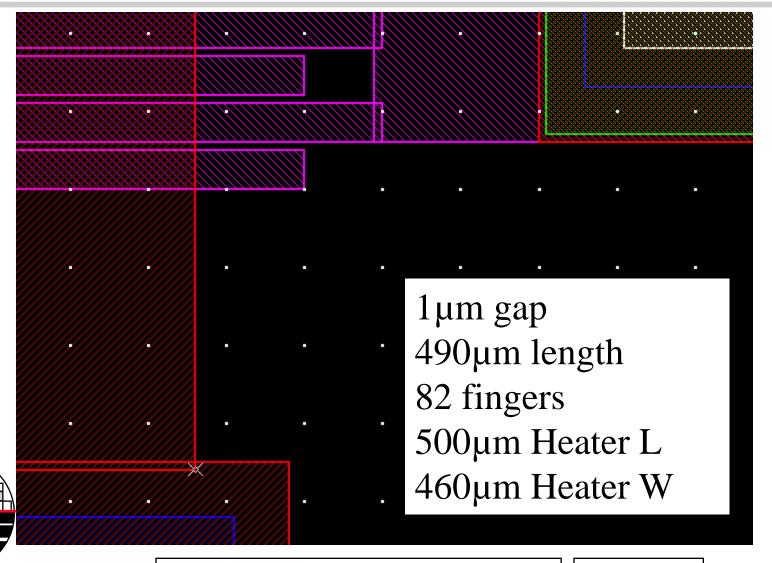
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CHEMICAL SENSOR OR HUMIDITY SENSOR

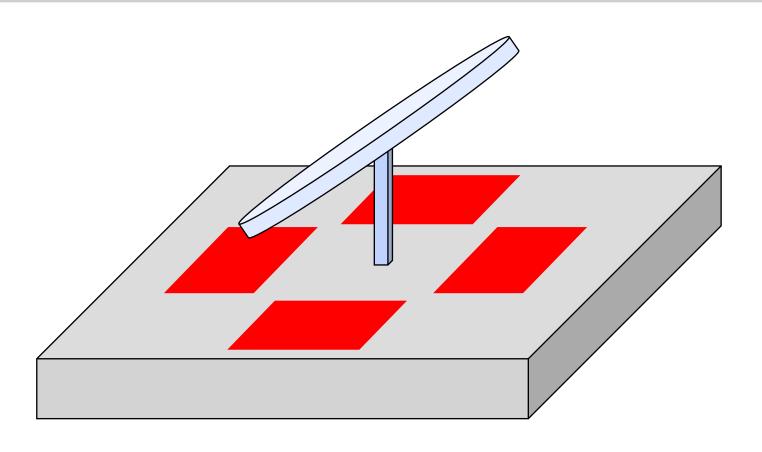


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CHEMICAL SENSOR OR HUMIDITY SENSOR



MIRROR

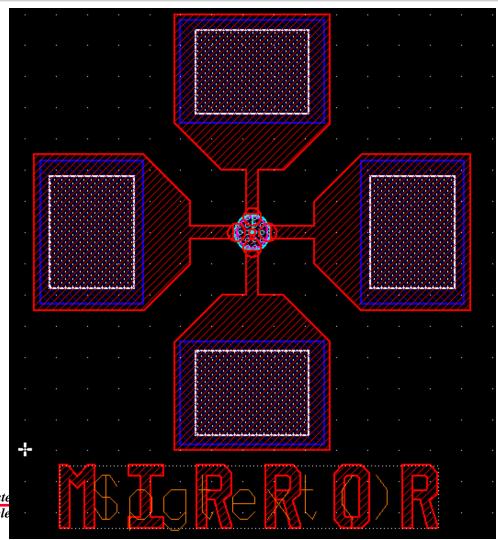




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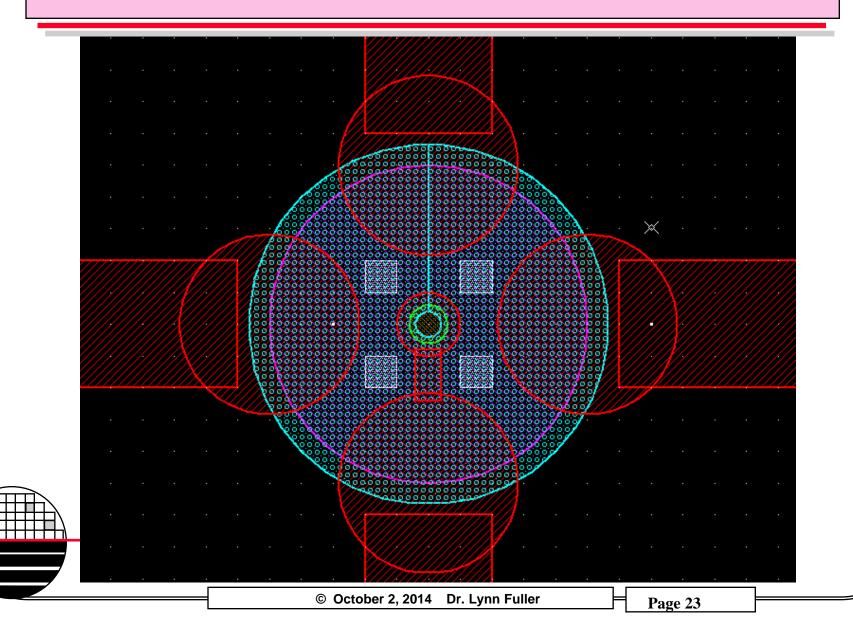
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MIRROR

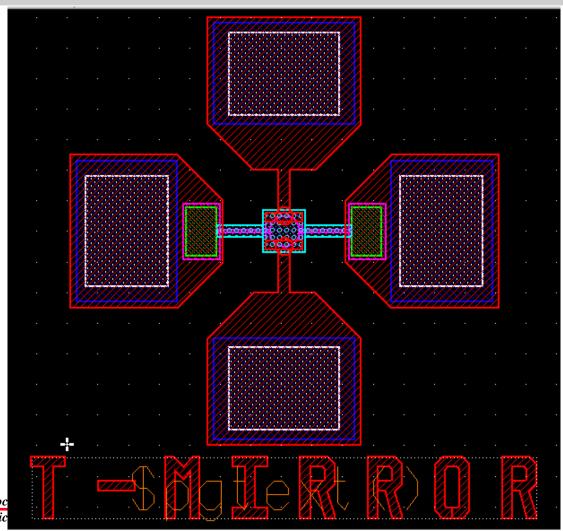


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MIRRORS

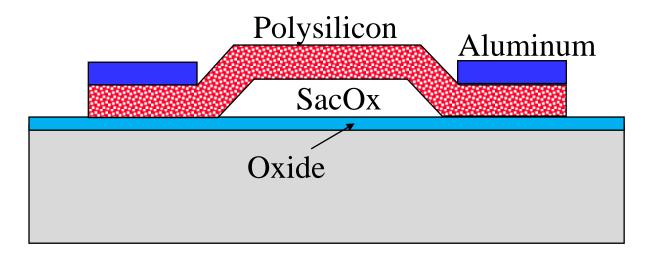


TORSIONAL MIRROR

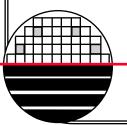


Roc Mic

HEATERS AND TEMPERATURE SENSORS



Resistor Heater Thermocouple Sensor Resistor Sensor



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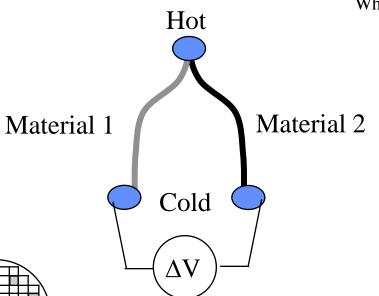
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SEEBECK EFFECT

When two dissimilar conductors are connected together a voltage may be generated if the junction is at a temperature different from the temperature at the other end of the conductors (cold junction) This is the principal behind the thermocouple and is called the Seebeck effect.

 $\Delta V = \alpha_1 (T_{cold} - T_{hot}) + \alpha_2 (T_{hot} - T_{cold}) = (\alpha_1 - \alpha_2)(T_{hot} - T_{cold})$

Where α_1 and α_2 are the Seebeck coefficients for materials 1 and 2



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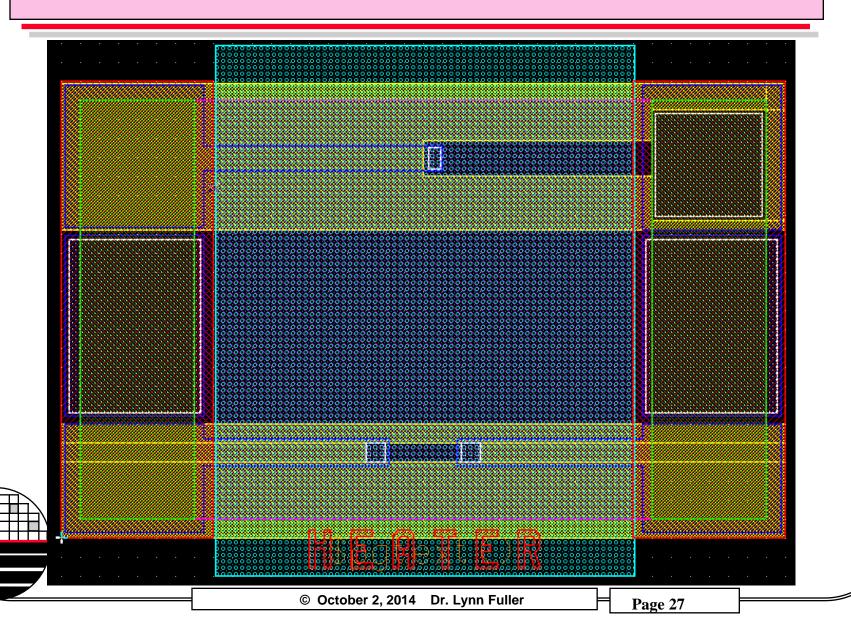
Table 2.6 The Seebeck Coefficients Relative to Platinum for Selected Metals and for n- and p-Type Polysilicon

| | μV/K | | μV/K |
|----|-------|-------------------|------|
| Bi | -73.4 | Ag | 7.4 |
| Ni | -14.8 | Cu | 7.6 |
| Pa | -5.7 | Zn | 7.6 |
| Pt | 0 | Au | 7.8 |
| Ta | 3.3 | w | 11.2 |
| Al | 4.2 | Mo | 14.5 |
| Sn | 4.2 | n-poly (30 Ω/□) | -100 |
| Mg | 4.4 | n-poly (2600 Ω/□) | -450 |
| Ir | 6.5 | p-poly (400 Ω/□) | 270 |
| | | [2:400] | |

Note: The sheet resistance is given for the 0.38-µm-thick polysilicon films. Polysilicon is an attractive material for the fabrication of thermocouples and thermopiles because of its large Seebeck coefficient.

Nadim Maluf, Kirt Williams, An Introduction to Microelectromechanical Systems Engineering, 2nd Ed. 2004

HEATER AND TEMPERATURE SENSORS

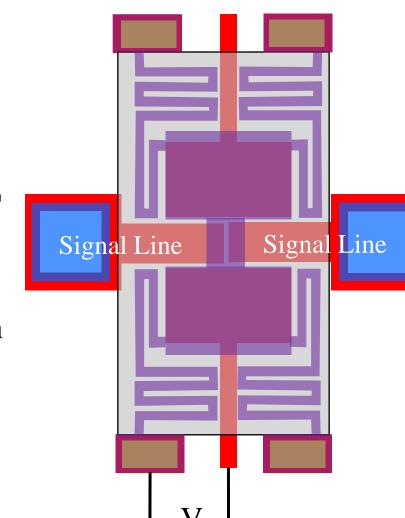


MEMS SWITCH

Signal Line

Signal Line

Electrostatic actuation (V) pulls down contactor to make connection along the signal line.

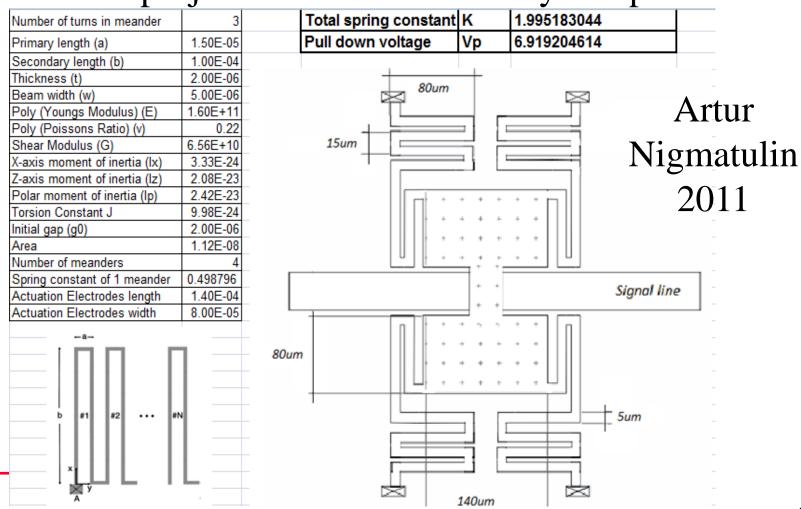




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SWITCH CALCULATIONS PLUS DIMENSIONS

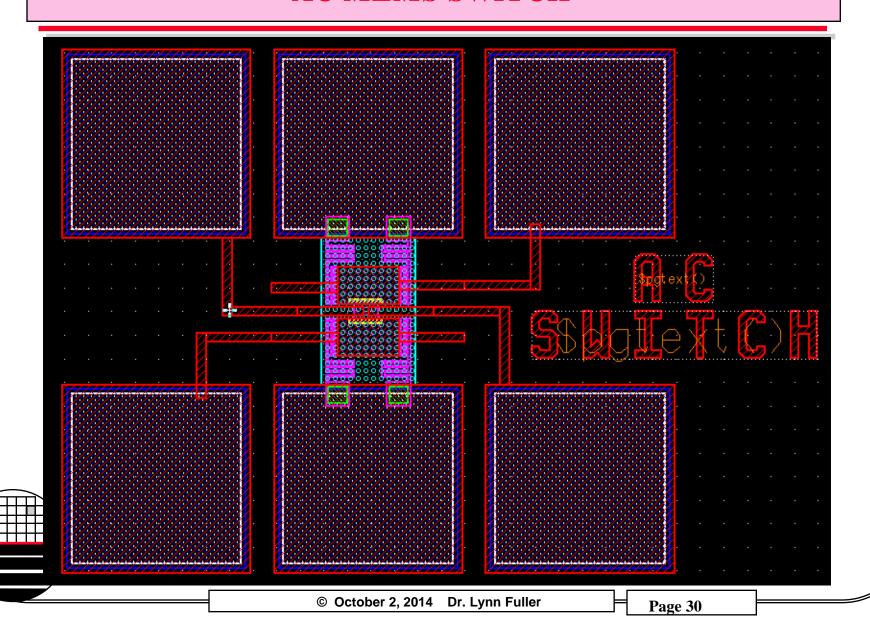
Each project has 5mm x 5mm layout space



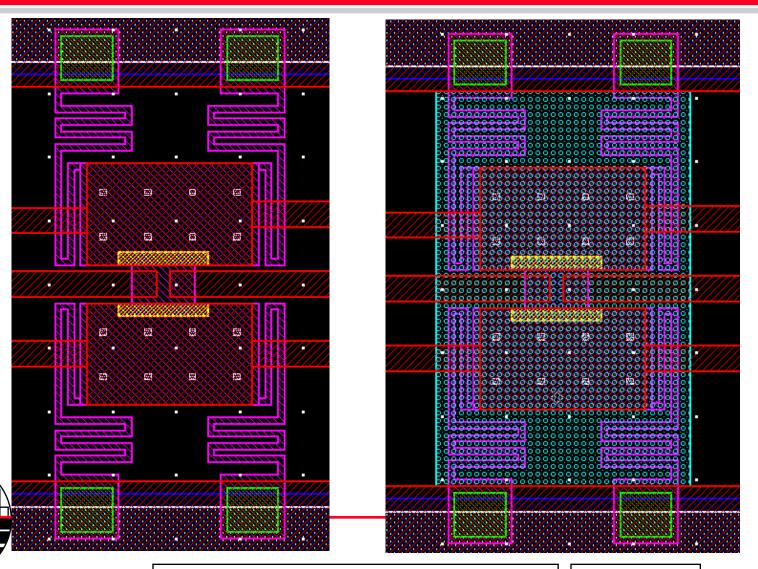
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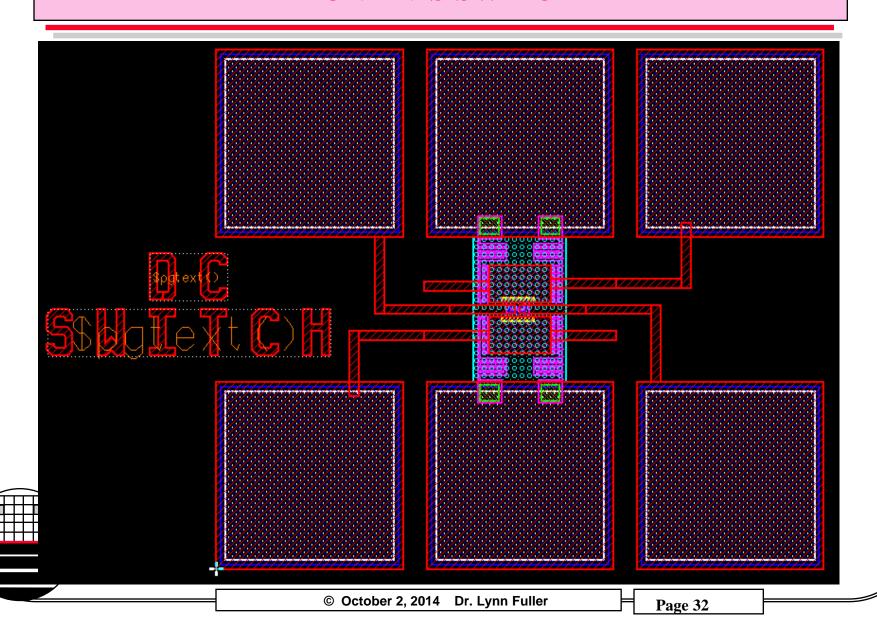
AC MEMS SWITCH

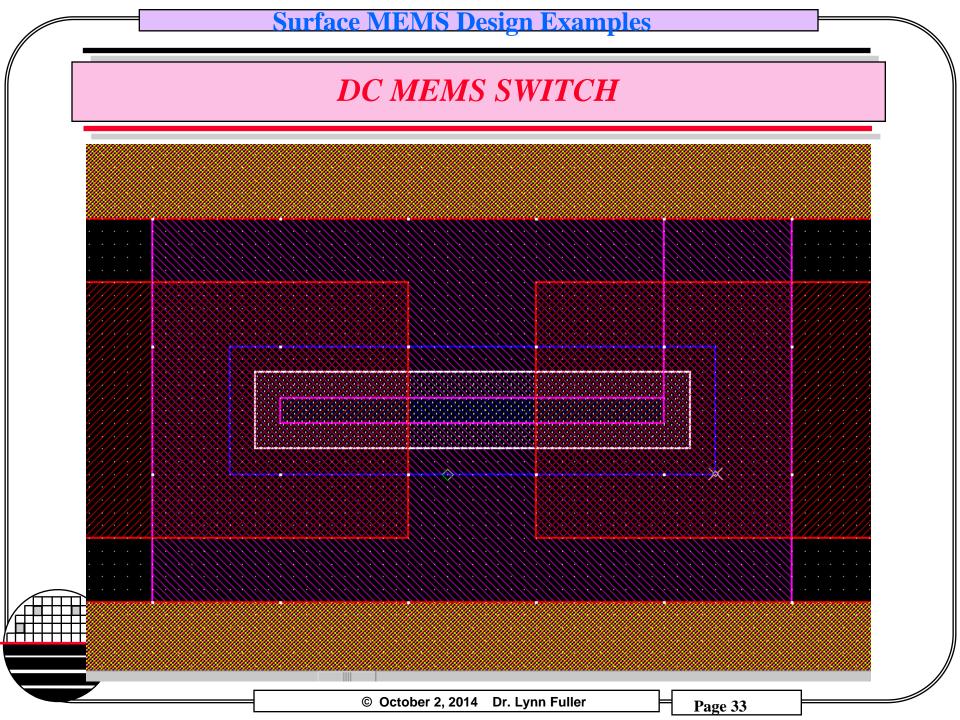


AC MEMS SWITCH

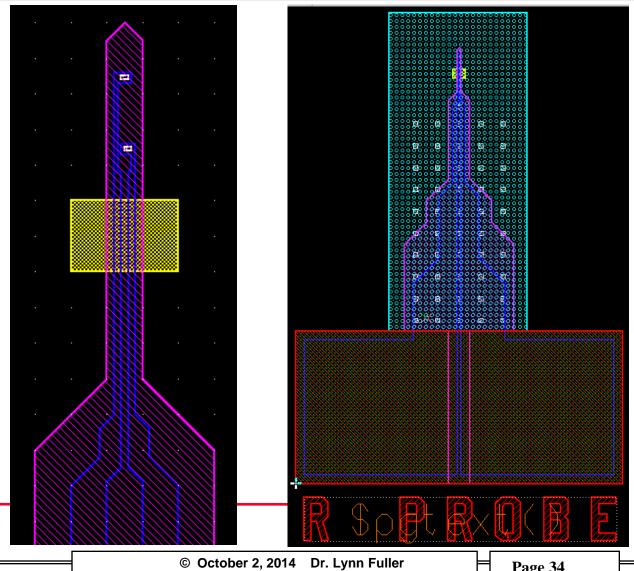


DC MEMS SWITCH



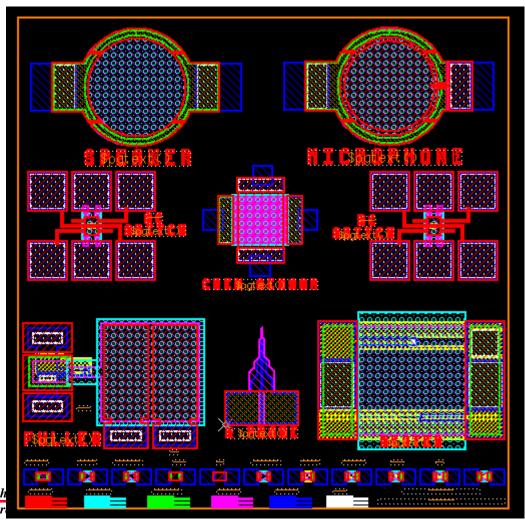


PROBE



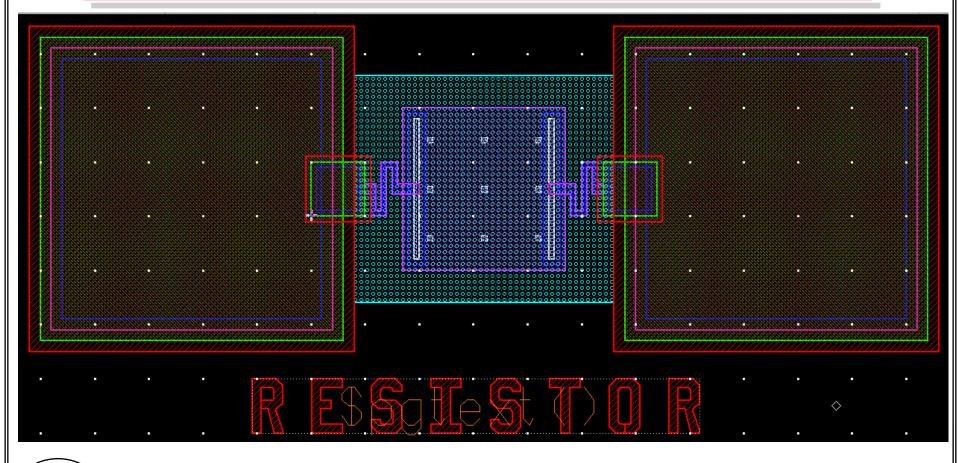


ALL ABOVE CELLS



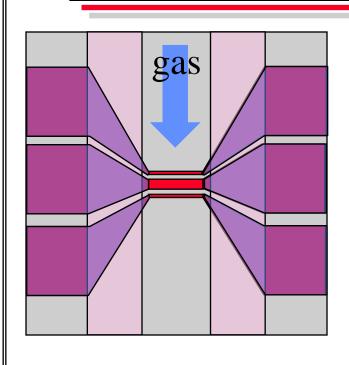
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RESISTOR - BOLOMETER

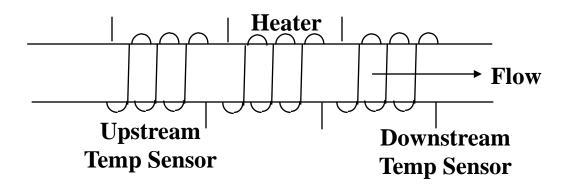


Resistor is suspended in air.

THERMAL FLOW SENSORS



Spring 2003
EMCR 890 Class Project
Dr. Lynn Fuller



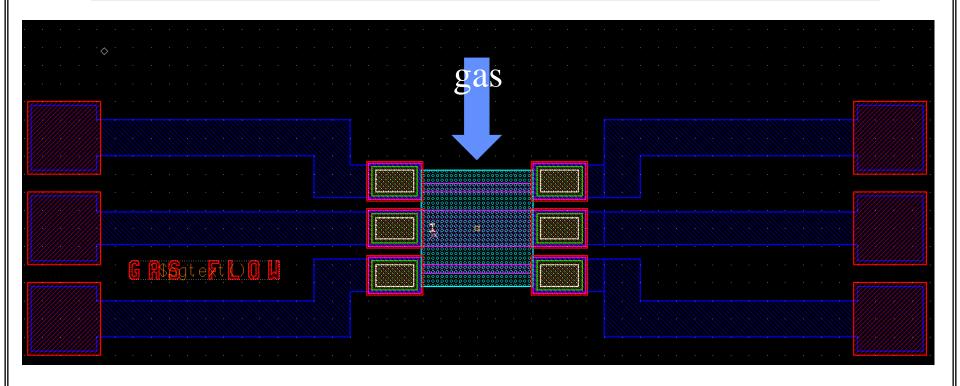
Polysilicon Aluminum
SacOx

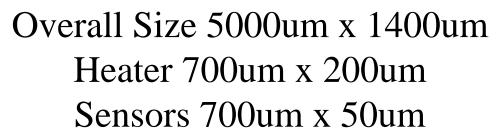
Si3N4

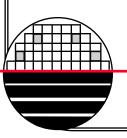
Silicon Substrate

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GAS FLOW SENSOR









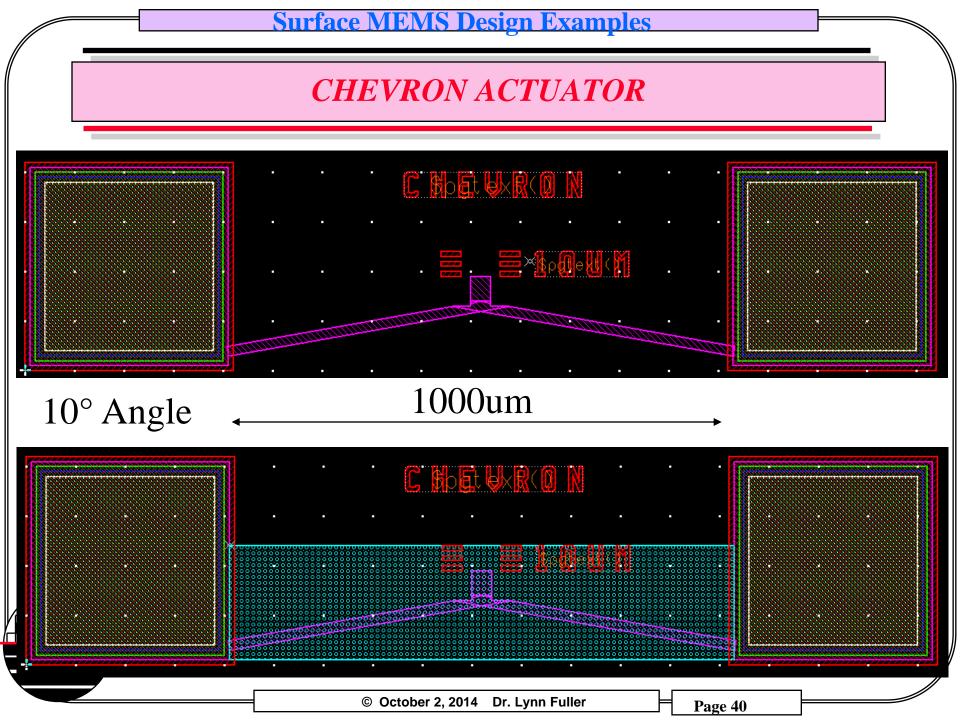
CHEVRON ACTUATOR

10° Angle — 1000um

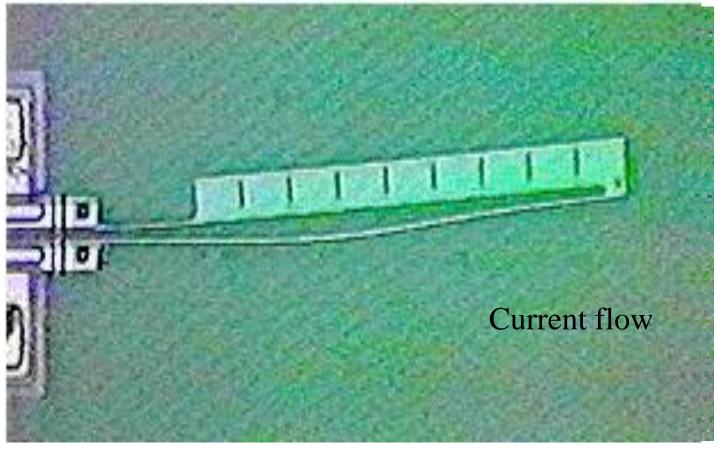
Thermal Expansion for Si is 2.33E-6/°C Current flow causes heating and movement

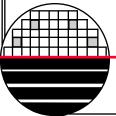
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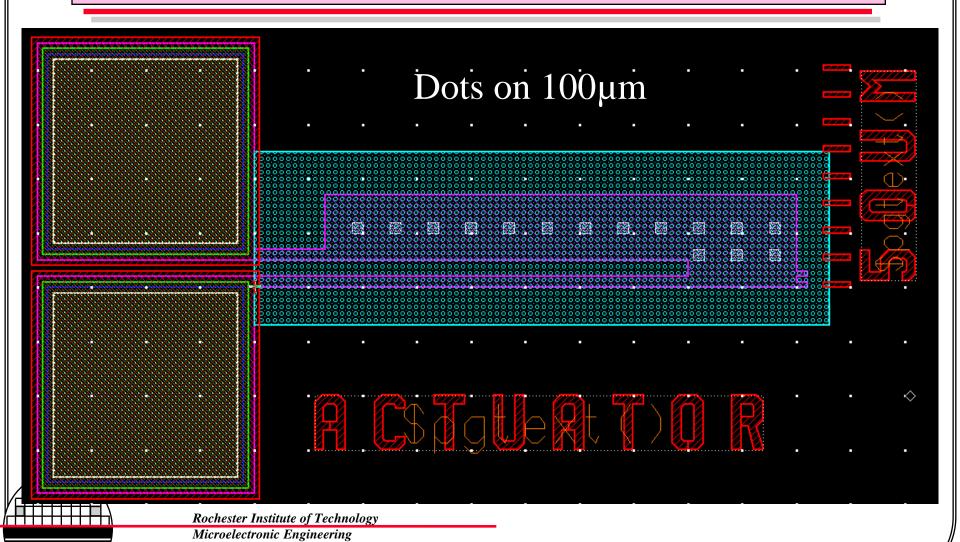


POLYSILICON THERMAL ACTUATORS





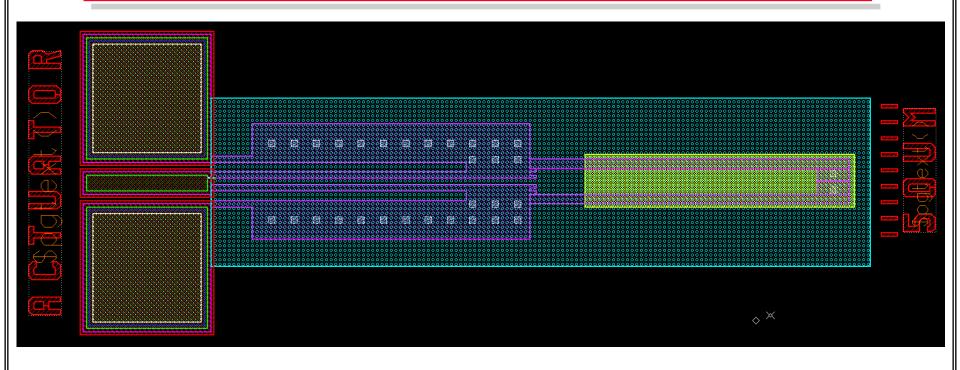
TWO ARM THERMAL ACTUATOR



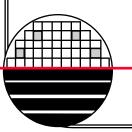
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MICRO GRIPPER



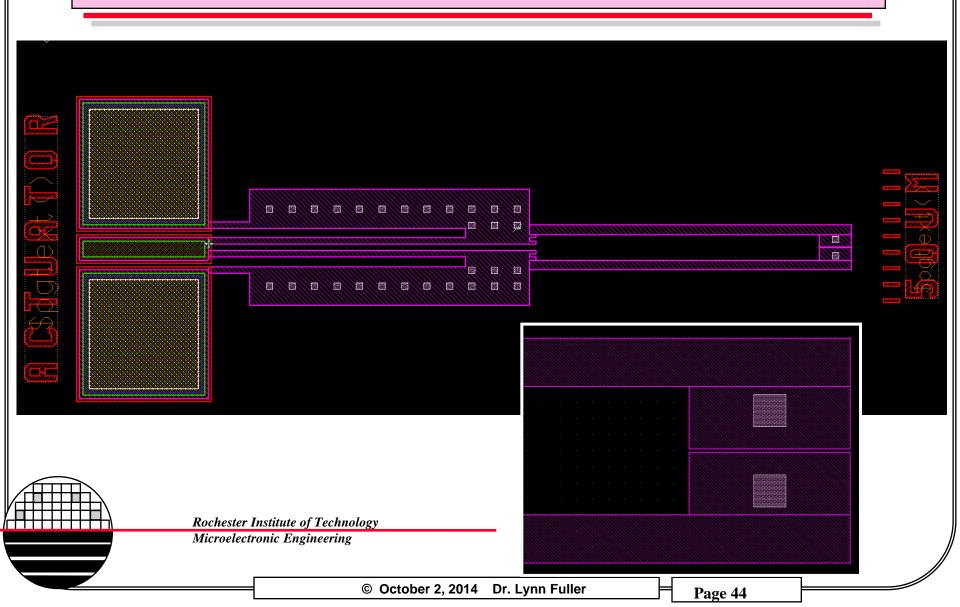
$2000 \mu m$



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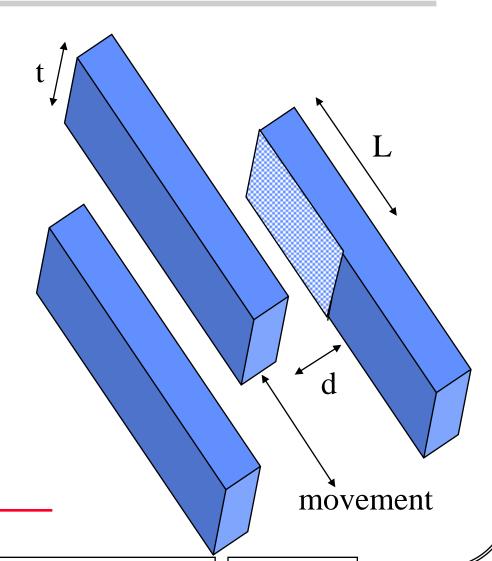
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MICRO GRIPPER



CALCULATION OF DISPLACEMENT VS VOLTAGE

 $F = \varepsilon r \varepsilon o t V^2 / 2 d$



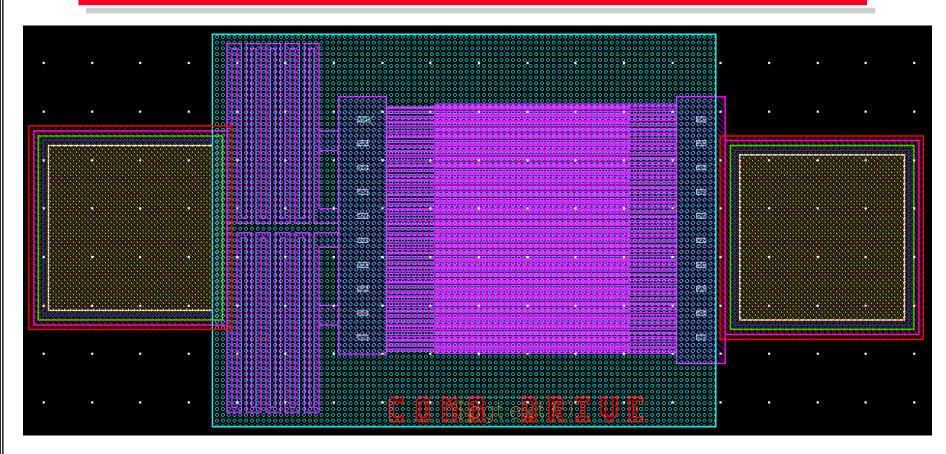


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COMB DRIVE ACTUATOR





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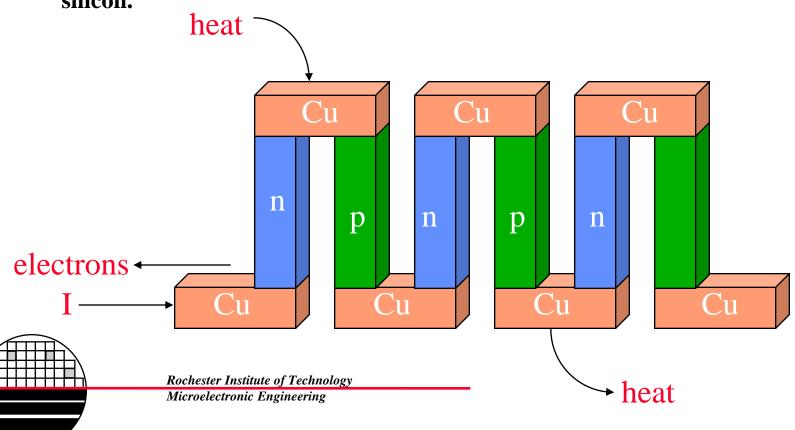
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COMB DRIVE ACTUATOR

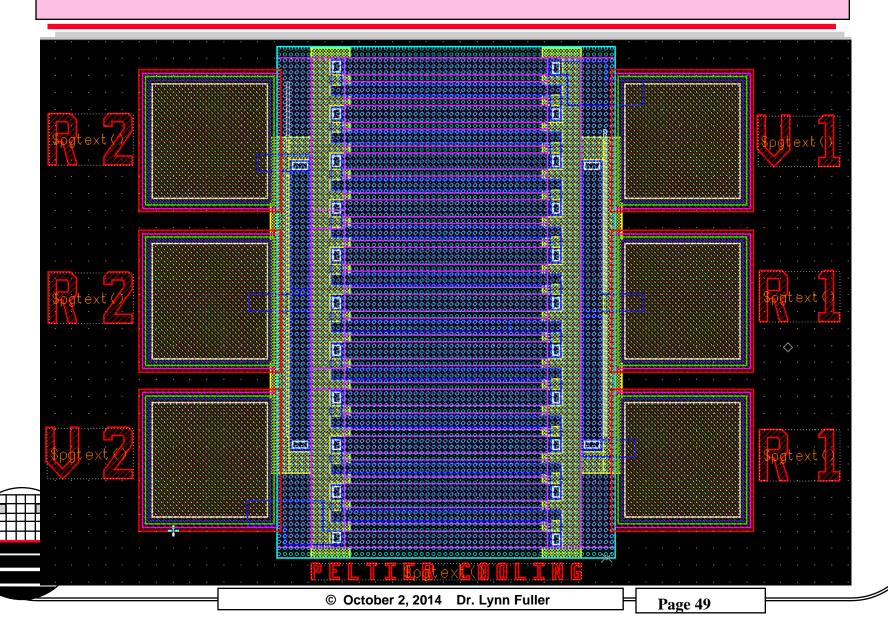
Dots - 1um Markers

PELTIER EFFECT

Heat pump device that works on the gain in electron energy for materials with low work function and the loss in energy for materials with higher work function. Electrons are at higher energy (lower work function) in n-type silicon.



PELTIER COOLING



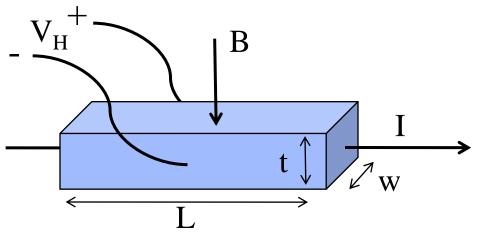
Surface MEMS Design Examples PELTIER COOLING © October 2, 2014 Dr. Lynn Fuller Page 50

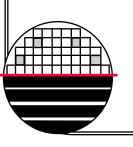
THE HALL EFFECT

The Hall effect was discovered in 1879 by Edwin H Hall.

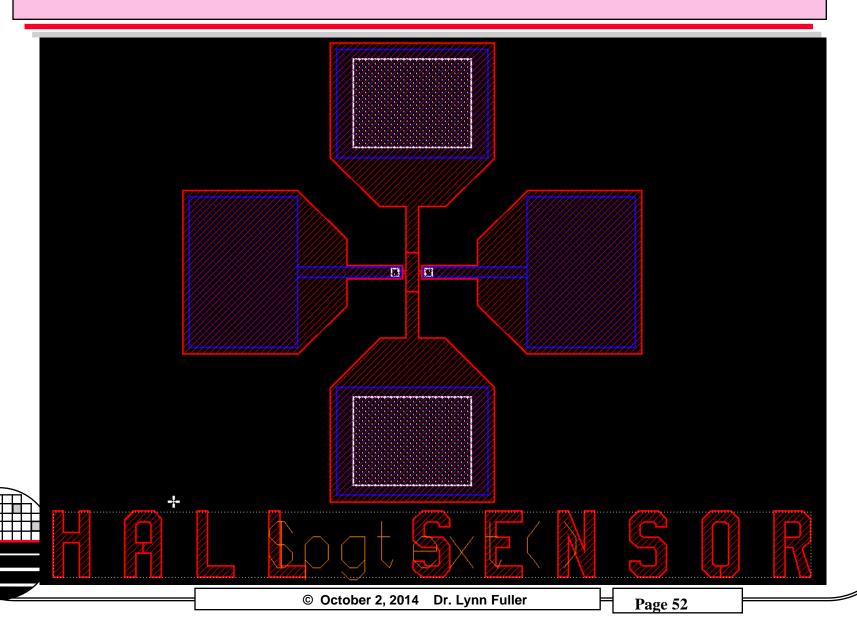
The Hall voltage (V_H) is created across a conductor, transverse to the current flow (I) and perpendicular to a magnetic field (B). The Hall coefficient is defined as the ratio of the Hall voltage to the product of Current and magnetic field. The Hall coefficient is a function of the carrier type (+ or -), charge (q=1.6E-19), and carrier concentration (n).

$$V_{H} = \frac{-IB}{q n t}$$

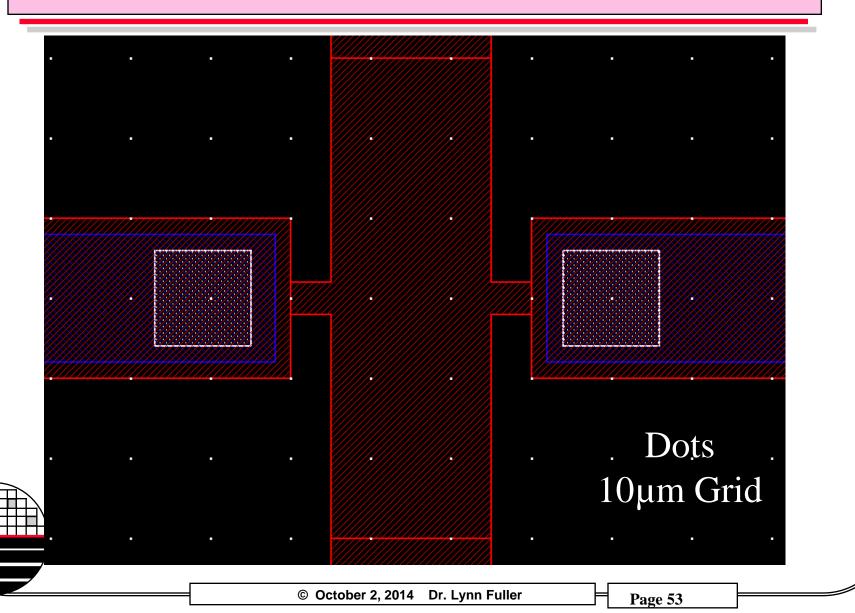




HALL EFFECT MAGNETIC FIELD SENSOR



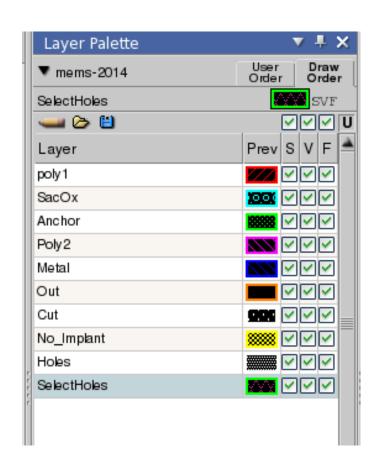
HALL EFFECT MAGNETIC FIELD SENSOR

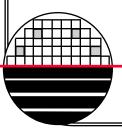


HOMEWORK – DESIGN EXAMPLES

- 1. Draw the Layout for a device you would like to build.
- 2. Export the GDS-II file and email it to your instructor.

Use the process / tools/ritpub/process/mems-2014





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HOMEWORK – DESIGN PRESENTATION

- 1. Prepare a PowerPoint presentation and present it to the class.
 - 1. Title page, Name, Date, Rochester Institute of Technology, MCEE770 MEMS Fabrication
 - 2. Introduction and Overview (1 or 2 pages)
 - 3. Appropriate Calculations (1 or 2 pages)
 - 4. Layout (a few pages) with dimensions added, zoom in to some areas, show all layers, show selected layers
- 2. Bring your PowerPoint on a Flash Drive and load on the instructors computer at the start of class.

